

## High Speed Optocoupler, 1 MBd, Photodiode with Transistor Output

### Features

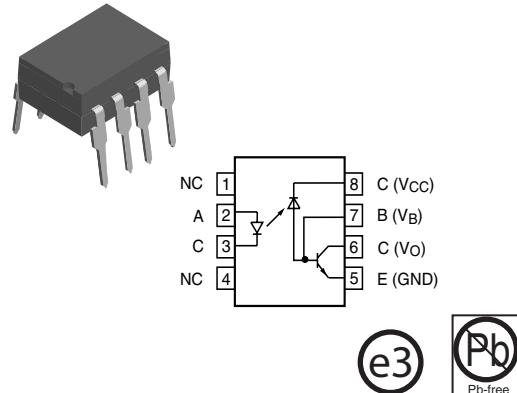
- Isolation Test Voltage: 5300 V<sub>RMS</sub>
- TTL Compatible
- High Bit Rates: 1.0 Mbit/s
- High Common-Mode Interference Immunity
- Bandwidth 2.0 MHz
- Open-Collector Output
- External Base Wiring Possible
- Lead-free component
- Component in accordance to RoHS 2002/95/EC and WEEE 2002/96/EC

### Agency Approvals

- UL1577, File No. E52744 System Code H or J, Double Protection
- DIN EN 60747-5-2 (VDE0884)  
DIN EN 60747-5-5 pending  
Available with Option 1
- CSA 93751

### Description

The 6N135 and 6N136 are optocouplers with a GaAlAs infrared emitting diode, optically coupled with an integrated photo detector which consists of a photo diode and a high-speed transistor in a DIP-8 plastic package.



Signals can be transmitted between two electrically separated circuits up to frequencies of 2.0 MHz. The potential difference between the circuits to be coupled should not exceed the maximum permissible reference voltages

### Order Information

Part	Remarks
6N135	CTR ≥ 7 %, DIP-8
6N136	CTR ≥ 19 %, DIP-8
6N135-X007	CTR ≥ 7 %, SMD-8 (option 7)
6N136-X006	CTR ≥ 19 %, DIP-8 400 mil (option 6)
6N136-X007	CTR ≥ 19 %, SMD-8 (option 7)
6N136-X009	CTR ≥ 19 %, SMD-8 (option 9)

For additional information on the available options refer to Option Information.

### Absolute Maximum Ratings

T<sub>amb</sub> = 25 °C, unless otherwise specified

Stresses in excess of the absolute Maximum Ratings can cause permanent damage to the device. Functional operation of the device is not implied at these or any other conditions in excess of those given in the operational sections of this document. Exposure to absolute Maximum Rating for extended periods of the time can adversely affect reliability.

### Input

Parameter	Test condition	Symbol	Value	Unit
Reverse voltages		V <sub>R</sub>	5.0	V
Forward current		I <sub>F</sub>	25	mA
Peak forward current	t = 1.0 ms, duty cycle 50 %	I <sub>FSM</sub>	50	mA
Maximum surge forward current	t ≤ 1.0 μs, 300 pulses/s		1.0	A
Thermal resistance		R <sub>th</sub>	700	K/W
Power dissipation	T <sub>amb</sub> = 70 °C	P <sub>diss</sub>	45	mW

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## Output

Parameter	Test condition	Symbol	Value	Unit
Supply voltage		$V_S$	- 0.5 to 15	V
Output voltage		$V_O$	- 0.5 to 15	V
Emitter-base voltage		$V_{EBO}$	5.0	V
Output current		$I_O$	8.0	mA
Maximum output current			16	mA
Base current		$I_B$	5.0	mA
Thermal resistance			300	K/W
Power dissipation	$T_{amb} = 70 \text{ }^{\circ}\text{C}$	$P_{diss}$	100	mW

## Coupler

Parameter	Test condition	Symbol	Value	Unit
Isolation test voltage (between emitter and detector climate per DIN 50014 part 2, NOV 74)	$t = 1.0 \text{ s}$	$V_{ISO}$	5300	$V_{RMS}$
Pollution degree (DIN VDE 0109)			2.0	
Creepage			$\geq 7.0$	mm
Clearance			$\geq 7.0$	mm
Comparative tracking index per DIN IEC112/VDE 0303 part 1, group IIIa per DIN VDE 6110			175	
Isolation resistance	$V_{IO} = 500 \text{ V}, T_{amb} = 25 \text{ }^{\circ}\text{C}$	$R_{IO}$	$\geq 10^{12}$	$\Omega$
	$V_{IO} = 500 \text{ V}, T_{amb} = 100 \text{ }^{\circ}\text{C}$	$R_{IO}$	$\geq 10^{11}$	$\Omega$
Storage temperature range		$T_{stg}$	- 55 to + 125	$^{\circ}\text{C}$
Ambient temperature range		$T_{amb}$	- 55 to + 100	$^{\circ}\text{C}$
Soldering temperature	max. $\leq 10 \text{ s}$ , dip soldering $\geq 0.5 \text{ mm}$ from case bottom	$T_{sld}$	260	$^{\circ}\text{C}$

## Electrical Characteristics

$T_{amb} = 25 \text{ }^{\circ}\text{C}$ , unless otherwise specified

Minimum and maximum values are testing requirements. Typical values are characteristics of the device and are the result of engineering evaluation. Typical values are for information only and are not part of the testing requirements.

## Input

Parameter	Test condition	Symbol	Min	Typ.	Max	Unit
Forward voltage	$I_F = 16 \text{ mA}$	$V_F$		1.6	1.9	V
Breakdown voltage	$I_R = 10 \mu\text{A}$	$V_{BR}$	5.0			V
Reverse current	$V_R = 5.0 \text{ V}$	$I_R$		0.5	10	$\mu\text{A}$
Capacitance	$V_R = 0 \text{ V}, f = 1.0 \text{ MHz}$	$C_O$		125		pF
Temperature coefficient, forward voltage	$I_F = 16 \text{ mA}$	$\Delta V_F/\Delta T_A$		-1.7		$\text{mV}/^{\circ}\text{C}$

**Output**

Parameter	Test condition	Part	Symbol	Min	Typ.	Max	Unit
Logic low supply current	$I_F = 16 \text{ mA}, V_O \text{ open}, V_{CC} = 15 \text{ V}$		$I_{CCL}$		150		$\mu\text{A}$
Supply current, logic high	$I_F = 0 \text{ mA}, V_O \text{ open}, V_{CC} = 15 \text{ V}$		$I_{CCH}$		0.01	1	$\mu\text{A}$
Output voltage, output low	$I_F = 16 \text{ mA}, V_{CC} = 4.5 \text{ V}, I_O = 1.1 \text{ mA}$	6N135	$V_{OL}$		0.1	0.4	V
	$I_F = 16 \text{ mA}, V_{CC} = 4.5 \text{ V}, I_O = 2.4 \text{ mA}$				0.1	0.4	V
Output current, output high	$I_F = 0 \text{ mA}, V_O = V_{CC} = 5.5 \text{ V}$		$I_{OH}$		3.0	500	nA
	$I_F = 0 \text{ mA}, V_O = V_{CC} = 15 \text{ V}$		$I_{OH}$		0.01	1	$\mu\text{A}$

**Coupler**

Parameter	Test condition	Symbol	Min	Typ.	Max	Unit
Capacitance (input-output)	$f = 1.0 \text{ MHz}$	$C_{IO}$		0.6		pF

**Current Transfer Ratio**

Parameter	Test condition	Part	Symbol	Min	Typ.	Max	Unit
Current Transfer Ratio	$I_F = 16 \text{ mA}, V_O = 0.4 \text{ V}, V_{CC} = 4.5 \text{ V}$	6N135	CTR	7	16		%
		6N136	CTR	19	35		%
	$I_F = 16 \text{ mA}, V_O = 0.5 \text{ V}, V_{CC} = 4.5 \text{ V}$	6N135	CTR	5			%
		6N136	CTR	15			%

**Switching Characteristics**

Parameter	Test condition	Part	Symbol	Min	Typ.	Max	Unit
High-low	$I_F = 16 \text{ mA}, V_{CC} = 5.0 \text{ V}, R_L = 4.1 \text{ k}\Omega$	6N135	$t_{PHL}$		0.3	1.5	$\mu\text{s}$
	$I_F = 16 \text{ mA}, V_{CC} = 5.0 \text{ V}, R_L = 1.9 \text{ k}\Omega$	6N136	$t_{PHL}$		0.2	0.8	$\mu\text{s}$
Low-high	$I_F = 16 \text{ mA}, V_{CC} = 5.0 \text{ V}, R_L = 4.1 \text{ k}\Omega$	6N135	$t_{PLH}$		0.3	1.5	$\mu\text{s}$
	$I_F = 16 \text{ mA}, V_{CC} = 5.0 \text{ V}, R_L = 1.9 \text{ k}\Omega$	6N136	$t_{PLH}$		0.2	0.8	$\mu\text{s}$

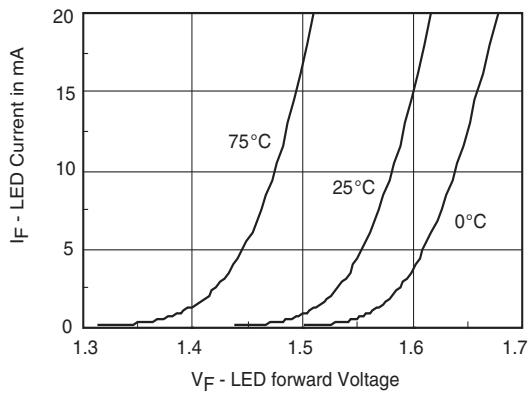
**Common Mode Transient Immunity**

Parameter	Test condition	Part	Symbol	Min	Typ.	Max	Unit
High	$I_F = 0 \text{ mA}, V_{CM} = 10 \text{ V}_{P-P}, V_{CC} = 5.0 \text{ V}, R_L = 4.1 \text{ k}\Omega$	6N135	$  CM_H  $		1000		$V/\mu\text{s}$
	$I_F = 0 \text{ mA}, V_{CM} = 10 \text{ V}_{P-P}, V_{CC} = 5.0 \text{ V}, R_L = 1.9 \text{ k}\Omega$	6N136	$  CM_H  $		1000		$V/\mu\text{s}$
Low	$I_F = 16 \text{ mA}, V_{CM} = 10 \text{ V}_{P-P}, V_{CC} = 5.0 \text{ V}, R_L = 4.1 \text{ k}\Omega$	6N135	$  CM_L  $		1000		$V/\mu\text{s}$
	$I_F = 16 \text{ mA}, V_{CM} = 10 \text{ V}_{P-P}, V_{CC} = 5.0 \text{ V}, R_L = 1.9 \text{ k}\Omega$	6N136	$  CM_L  $		1000		$V/\mu\text{s}$

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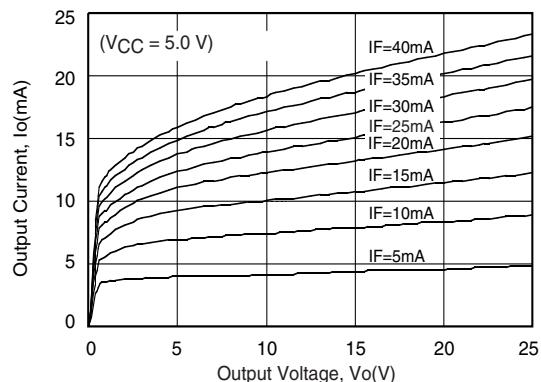
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**Typical Characteristics (Tamb = 25 °C unless otherwise specified)**



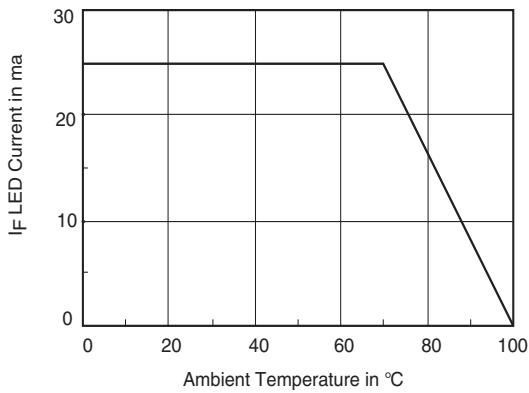
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Figure 1. LED Forward Current vs. Forward Voltage



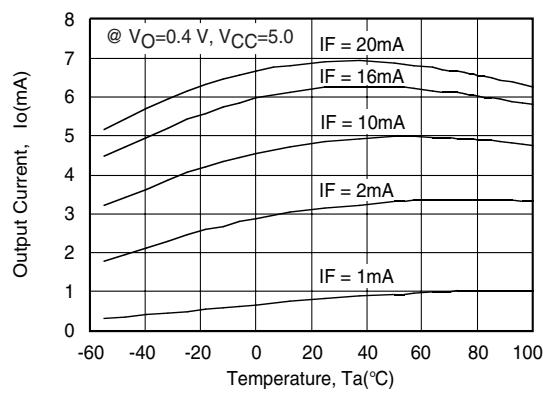
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Figure 4. Output Current vs. Output Voltage



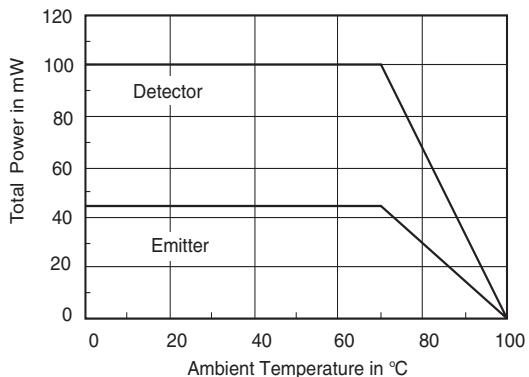
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Figure 2. Permissible Forward LED Current vs. Temperature



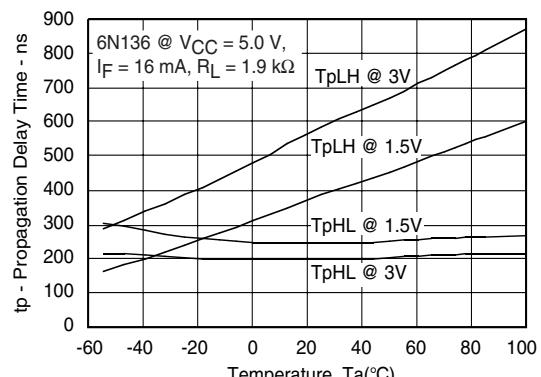
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Figure 5. Output Current vs. Temperature



i6n135\_05

Figure 3. Permissible Power Dissipation vs. Temperature



i6n135\_08

Figure 6. Propagation Delay vs. Ambient Temperature

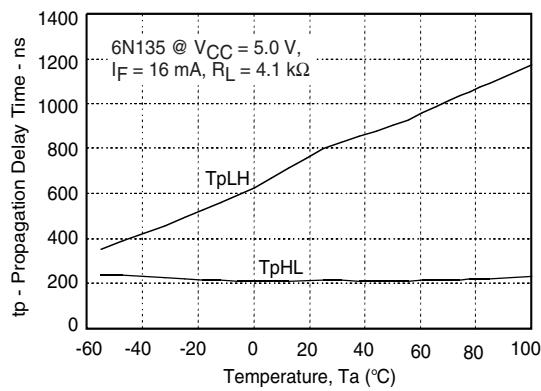


Figure 7. Propagation Delay vs. Ambient Temperature

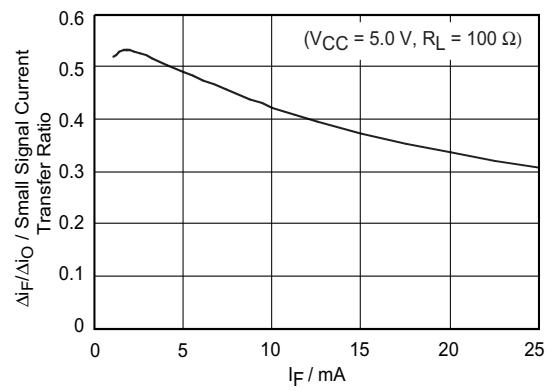


Figure 9. Small Signal Current Transfer Ratio vs. Quiescent Input Current

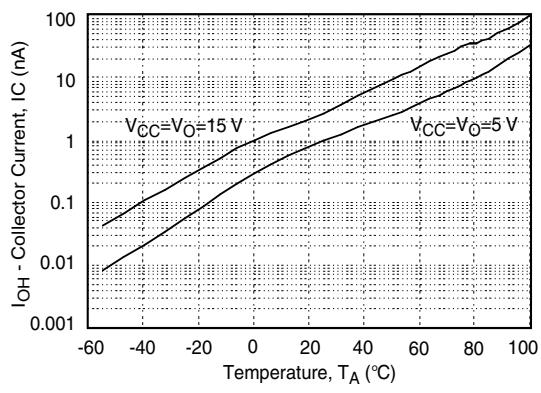


Figure 8. Logic High Output Current vs. Temperature

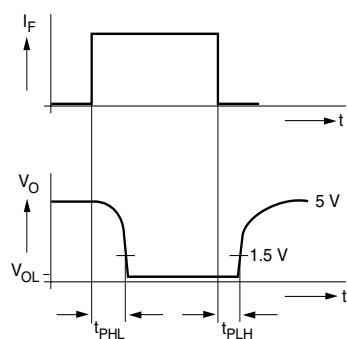
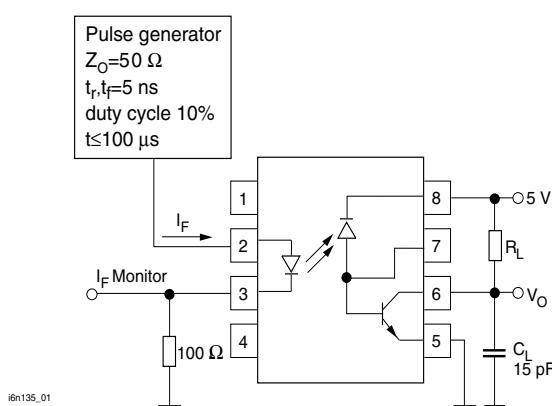


Figure 10. Switching Times

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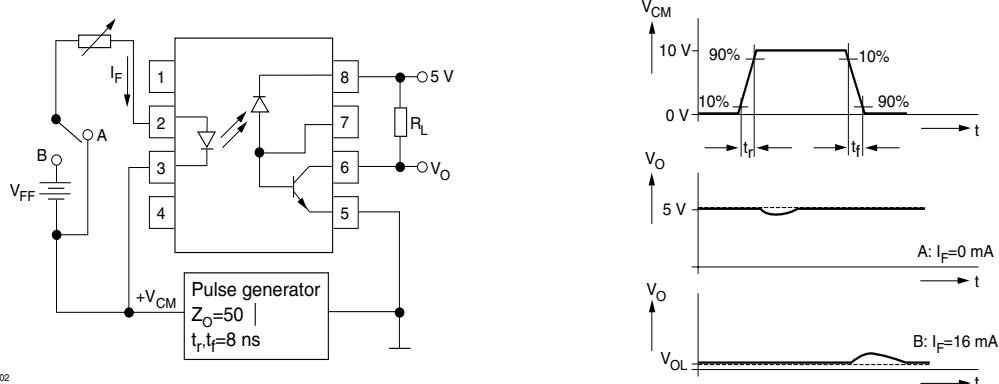
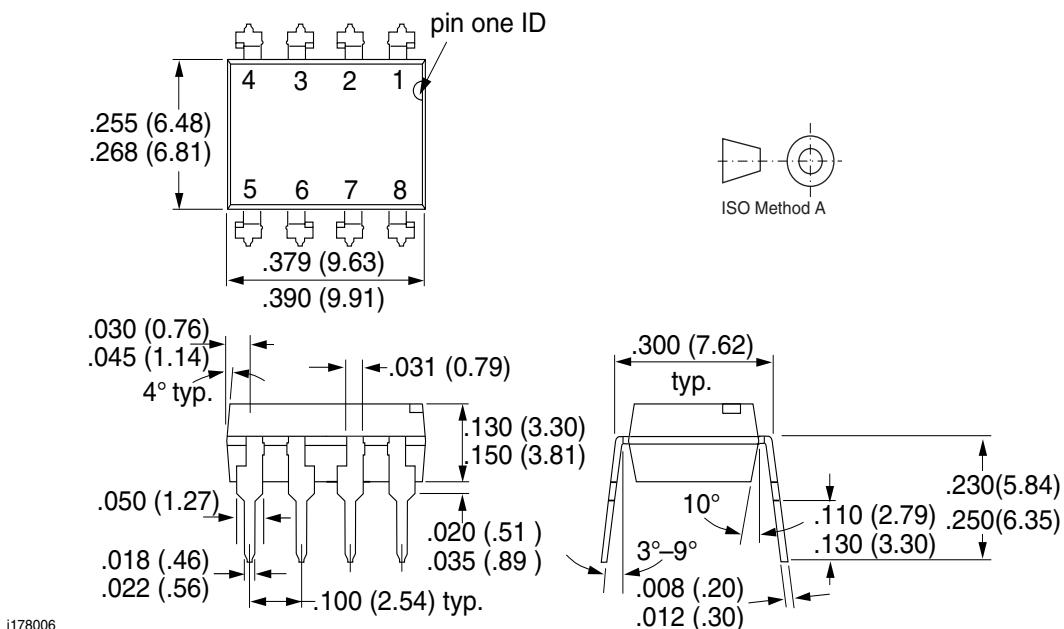


Figure 11. Common-Mode Interference Immunity

## Package Dimensions in Inches (mm)

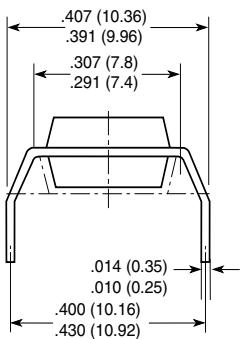


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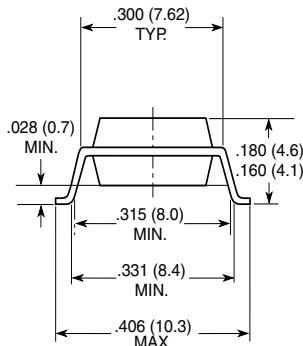
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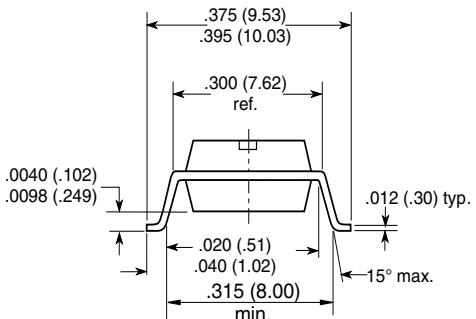
Option 6



Option 7



Option 9



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